

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1637	"10 nm" with insulat\$4 near4 (medium or layer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 15:15
L2	176	"10 nm" with insulat\$4 near4 (medium or layer) same (storage or capacit\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 15:16
L3	47	"10 nm" near5 insulat\$4 near4 (medium or layer) same (storage or capacit\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 15:16
S1	2	capacit\$5 same leak same dielectric same coupling same electric\$4 near2 power same residual same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 12:07
S2	2	capacit\$5 same leak same dielectric same coupling same electric\$4 near2 power same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 12:07
S3	3	capacit\$5 same leak same dielectric same electric\$4 near2 power same charge same decoupl\$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 12:08
S4	4	capacit\$5 same leak same dielectric same electric\$4 near2 power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 12:08
S5	15	capacit\$5 same leak same dielectric same power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 12:14
S8	15	leak near5 dielectric same power same (decoupl\$5 or coupl\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/07 13:12
S9	6	((("20020022961") or ("20040225199") or ("20040203413"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2007/08/07 14:43
S13	0	levinson.in. and electronic.clm. and capacitive.clm. and power.clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 13:56

## EAST Search History

S14	1	10/508865	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 14:05
S15	260	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 14:13
S16	5	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4) and leak with dielectric\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 14:15
S17	36	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same elaps\$4 near2 time same (charg\$4 or power\$4) and (leak or dielectric\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 16:14
S18	60	((electronic near1 (entity or device)) or (chip near1 card) or (ic near1 card) or (ic-card) or smartcard or smart-card or "smart card" or (microchip near1 card) or (micro-chip near1 card)) same external with (charg\$4 or power\$4) same coupl\$5 near15 switch\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/15 16:49
S20	2332	switch\$4 near4 decoupl\$5 same (power\$4 or electr\$7)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 13:55
S21	124	switch\$4 near4 decoupl\$5 same (power\$4 or electr\$7) with (passive or external\$4 or separate)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 08:07
S22	2	("4063229").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2007/08/16 08:11

## EAST Search History

S26	408	mos near5 capacit\$6 same dielectric same silicon with oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 13:56
S27	150	mos near5 capacit\$6 same dielectric with silicon adj1 oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 13:57
S28	44	mos near5 capacit\$6 near6 dielectric with silicon adj1 oxide	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/08/16 15:07